NAPSON CORPORATION

Non Contact Wafer Sorter

Model NC-3000F

1. Resisivitity measreument spec

Range	Accuracy(Linearity)	Repeatability
LOW(0.0006~0.03 ohm-cm)	≦ ±1% ~ 2%	≦ 0.7%
MIDDLE(0.03~0.6 ohm-cm))	≦ ±1% ~ 2%	≦ 0.7%
HIGH(0.6~18 ohm-cm)	≦ ±1% ~ 2%	≦ 0.7%
HIGH(18~100 ohm-cm)	≦ ±2% ~ 3% (Target ≦ ±2%)	≦ 1.5% (Target ≦ 1.0%)
S-HIGH (100~210 ohm-cm)	≦ ±3%~4%	≦ 3 %

Linearity: (AVE－STD) / STD × 100(%)，对比NC6800非接触式探头和4探针两种测试方法的结果，计算准确性和线性

Repeatability: σ / AVE × 100(%)

AVE = 用非接触式探头在同一点10次测量的平均值

/ 10 times average at the same point by noncontact sensor

STD = 用4探针在同一点10次测量的平均值，作为标准值

/ 10 times average at the same point by 4 point probe

2. Thickness measurement spec

Measuring range:	300～ 1,300μm
Measuring repeatability(σ or CV)	±0.15μm or 0.1%(Choose the big one) At 23±1°C, 55±10% RH
Display resolution:	0.1μm
Measuring point:	1 point (Center)

Note1) σ:10 times measurement

Note2) There is no environmental temperature change during the 10 times measurements

Note3) The above repeatability is only valid for sample provided by Napson (The sample is shipped with the machine.)

3. PN Type checker

0.02 ~2,000ohm.cm 范围内的硅片能准确识别 PN 型